



SURFACE MOUNT FAST SWITCHING RECTIFIER

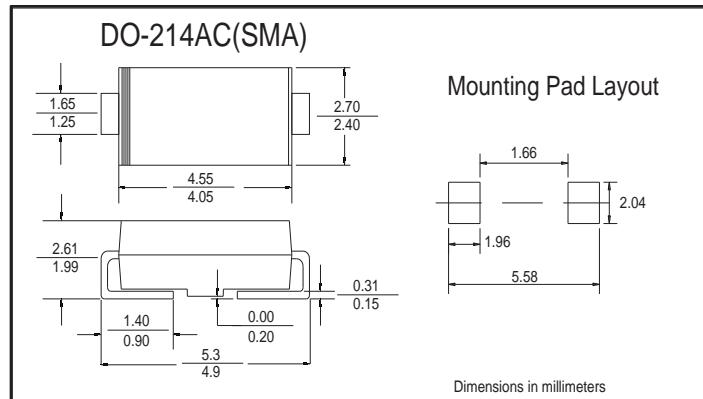
Reverse Voltage - 50 to 1000 Volts Forward Current - 1.0 Ampere

Features

- For surface mounted application
- Metal to silicon rectifier,majority carrier conduction
- Low forward voltage drop
- Easy pick and place
- High surge current capability
- Plastic material used carriers Underwriters Laboratory Classification 94-O
- Epitaxial construction
- High temperature soldering:
250°C/10 seconds at terminals

Mechanical Data

- Case: molded plastic
- Terminals:Solder plated
- Polarity:Indicated by cathode band
- Packaging:12mm tape EIA STD RS-481
- Weight:0.064gram



Maximum Ratings and Electrical Characteristics

Rating at 25°C ambient temperature unless otherwise specified.

Single phase, half wave,60Hz,resistive or inductive load. For capacitive load,derate current by 20%

Type Number		RS1A	RS1B	RS1D	RS1G	RS1J	RS1K	RS1M	UNITS
Maximum Repetitive Peak Reverse Voltage	V _{RRM}	50	100	200	400	600	800	1000	V
Maximum RMS Voltage	V _{RMS}	35	70	140	280	420	560	700	V
Maximum DC Blocking Voltage	V _{DC}	50	100	200	400	600	800	1000	V
Maximum Average Forward Rectified Current @ T _A =90°C	I _{F(AV)}				1.0				A
Peak Forward Surge Current,8.3 ms Single Half Sine-wave Superimposed on Rated Load (JEDEC method)	I _{FSM}				30				A
Maximum Instantaneous Forward Voltage (Note@1.0 A)	V _F				1.3				V
Maximum DC Reverse Current @ T _{ATA} =25°C At Rated DC Blocking Voltage @ T _A =125°C	I _R				5.0				uA
Maximun Reverse Recovery Time(Note 1)	T _{RR}		150		250		500		nS
Typical Thermal Resistance (Note 2)	R _{θ JL} R _{θ JA}			25					°C /W
Operating Junction Temperature Range	T _J		-55 to+125						°C
Storage Temperature Ranage	T _{STG}		-55 to+150						°C

NOTES: 1.Reverse Recovery Test conditions:I_F=0.5A,I_R=1.0A,I_{RR}=0.25A.

2. Thermal Resistance from Junction to Ambient and from Junction to Lead Mounted on P.C.B. with 0.2"x0.2" (5.0 x 5.0 mm) Copper Pad Areas.

■ Characteristics(Typical)

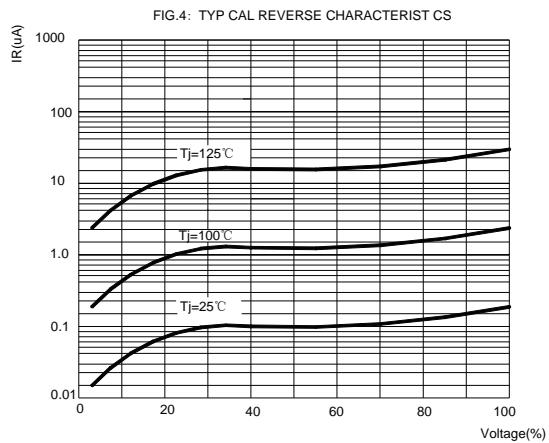
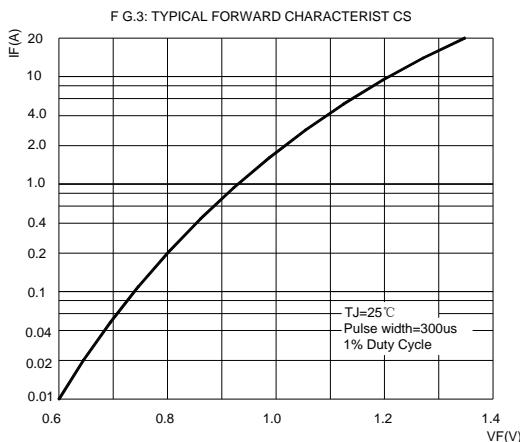
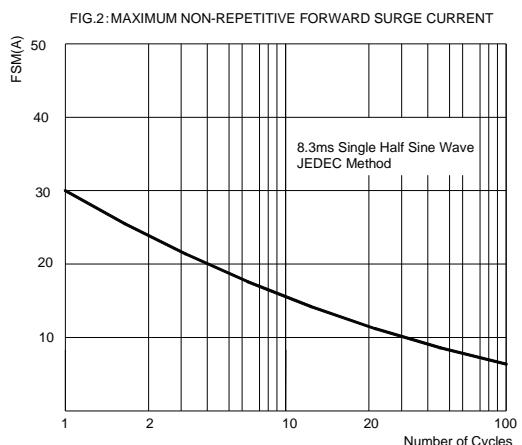
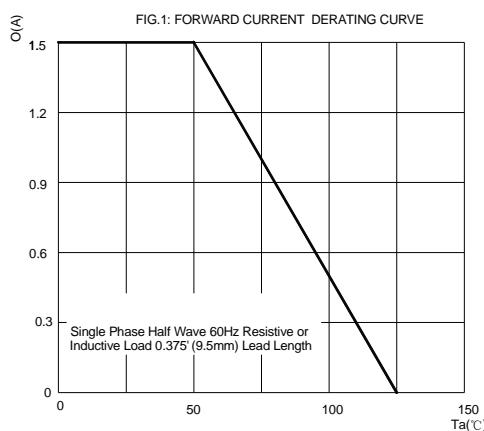


FIG.5: Diagram of circuit and Testing wave form of reverse recovery time

